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**DS2316**  
**Datasheet**  
**40MX and 42MX FPGA**





**Power Matters.™**

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# 1 Revision History

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The revision history describes the changes that were implemented in the document. The changes are listed by revision, starting with the most current publication.

## 1.1 Revision 15.0

The following is a summary of the changes in revision 15.0 of this document.

- [Table 15](#), page 21 is edited to add the footnote, VIH(Min) is 2.4V for A42MX36 family. This applies only to VCCI of 5V and is not applicable to VCCI of 3.3V
- [Table 22](#), page 25 is edited to add the footnote, VIH(Min) is 2.4V for A42MX36 family. This applies only to VCCI of 5V and is not applicable to VCCI of 3.3V
- [Table 23](#), page 25 is edited to add the footnote, VIH(Min) is 2.4V for A42MX36 family. This applies only to VCCI of 5V and is not applicable to VCCI of 3.3V

## 1.2 Revision 14.0

The following is a summary of the changes in revision 14.0 of this document.

- Added CQFP package information for A42MX16 device in [Product Profile](#), page 1 and [Ceramic Device Resources](#), page 4 (SAR 79522).
- Added Military (M) and MIL-STD-883 Class B (B) grades for CPGA 132 Package and added Commercial (C), Military (M), and MIL-STD-883 Class B (B) grades for CQFP 172 Package in [Temperature Grade Offerings](#), page 5 (SAR 79519)
- Changed Silicon Sculptor II to Silicon Sculptor in [Programming](#), page 12 (SAR 38754)
- Added [Figure 53](#), page 158 CQ172 package (SAR 79522).

## 1.3 Revision 13.0

The following is a summary of the changes in revision 13.0 of this document.

- Added [Figure 42](#), page 97 PQ144 Package for A42MX09 device (SAR 69776)
- Added [Figure 52](#), page 153 PQ132 Package for A42MX09 device (SAR 69776)

## 1.4 Revision 12.0

The following is a summary of the changes in revision 12.0 of this document.

- Added information on power-up behavior for A42MX24 and A42MX36 devices to the [Power Supply](#), page 13 (SAR 42096)
- Corrected the inadvertent mistake in the naming of the PL68 pin assignment table (SARs 48999, 49793)

## 1.5 Revision 11.0

The following is a summary of the changes in revision 11.0 of this document.

- The FuseLock logo and accompanying text was removed from the [User Security](#), page 12. This marking is no longer used on Microsemi devices ([PCN 0915](#))
- The [Development Tool Support](#), page 19 was updated (SAR 38512)

## 1.6 Revision 10.0

The following is a summary of the changes in revision 10.0 of this document.

- [Ordering Information](#), page 3 was updated to include lead-free package ordering codes (SAR 21968)
- The [User Security](#), page 12 was revised to clarify that although no existing security measures can give an absolute guarantee, Microsemi FPGAs implement the best security available in the industry (SAR 34673)

- The [Transient Current](#), page 13 is new (SAR 36930).
- Package names were revised according to standards established in [Package Mechanical Drawings](#) (SAR 34774)

## 1.7 Revision 9.0

The following is a summary of the changes in revision 9.0 of this document

- In [Table 20](#), page 23, the limits in VI were changed from -0.5 to VCCI + 0.5 to -0.5 to VCCA + 0.5
- In [Table 22](#), page 25,  $V_{OH}$  was changed from 3.7 to 2.4 for the min in industrial and military.  $V_{IH}$  had  $V_{CCI}$  and that was changed to VCCA

## 1.8 Revision 6.0

The following is a summary of the changes in revision 6.0 of this document.

- The [Ease of Integration](#), page 1 was updated
- The [Temperature Grade Offerings](#), page 5 is new
- The [Speed Grade Offerings](#), page 5 is new
- The [General Description](#), page 6 was updated
- The [MultiPlex I/O Modules](#), page 11 was updated
- The [User Security](#), page 12 was updated
- [Table 6](#), page 13 was updated
- The [Power Dissipation](#), page 14 was updated.
- The [Static Power Component](#), page 14 was updated
- The [Equivalent Capacitance](#), page 15 was updated
- [Figure 13](#), page 17 was updated
- [Table 10](#), page 18 was updated.
- [Figure 14](#), page 18 was updated.
- [Table 11](#), page 19 was updated.

## 2 40MX and 42MX FPGA Families

### 2.1 Features

The following sections list out various features of the 40MX and 42MX FPGA family devices.

#### 2.1.1 High Capacity

- Single-Chip ASIC Alternative
- 3,000 to 54,000 System Gates
- Up to 2.5 kbits Configurable Dual-Port SRAM
- Fast Wide-Decode Circuitry
- Up to 202 User-Programmable I/O Pins

#### 2.1.2 High Performance

- 5.6 ns Clock-to-Out
- 250 MHz Performance
- 5 ns Dual-Port SRAM Access
- 100 MHz FIFOs
- 7.5 ns 35-Bit Address Decode

#### 2.1.3 HiRel Features

- Commercial, Industrial, Automotive, and Military Temperature Plastic Packages
- Commercial, Military Temperature, and MIL-STD-883 Ceramic Packages
- QML Certification
- Ceramic Devices Available to DSCC SMD

#### 2.1.4 Ease of Integration

- Mixed-Voltage Operation (5.0 V or 3.3 V for core and I/Os), with PCI-Compliant I/Os
- Up to 100% Resource Utilization and 100% Pin Locking
- Deterministic, User-Controllable Timing
- Unique In-System Diagnostic and Verification Capability with Silicon Explorer II
- Low Power Consumption
- IEEE Standard 1149.1 (JTAG) Boundary Scan Testing

### 2.2 Product Profile

The following table gives the features of the products.

**Table 1 • Product profile**

Device	A40MX02	A40MX04	A42MX09	A42MX16	A42MX24	A42MX36
<b>Capacity</b>						
System Gates	3,000	6,000	14,000	24,000	36,000	54,000
SRAM Bits	–	–	–	–	–	2,560
<b>Logic Modules</b>						
Sequential	–	–	348	624	954	1,230
Combinatorial	295	547	336	608	912	1,184
Decode	–	–	–	–	24	24
<b>Clock-to-Out</b>	9.5 ns	9.5 ns	5.6 ns	6.1 ns	6.1 ns	6.3 ns
<b>SRAM Modules (64x4 or 32x8)</b>						
	–	–	–	–	–	10
<b>Dedicated Flip-Flops</b>	–	–	348	624	954	1,230

**Table 1 • Product profile**

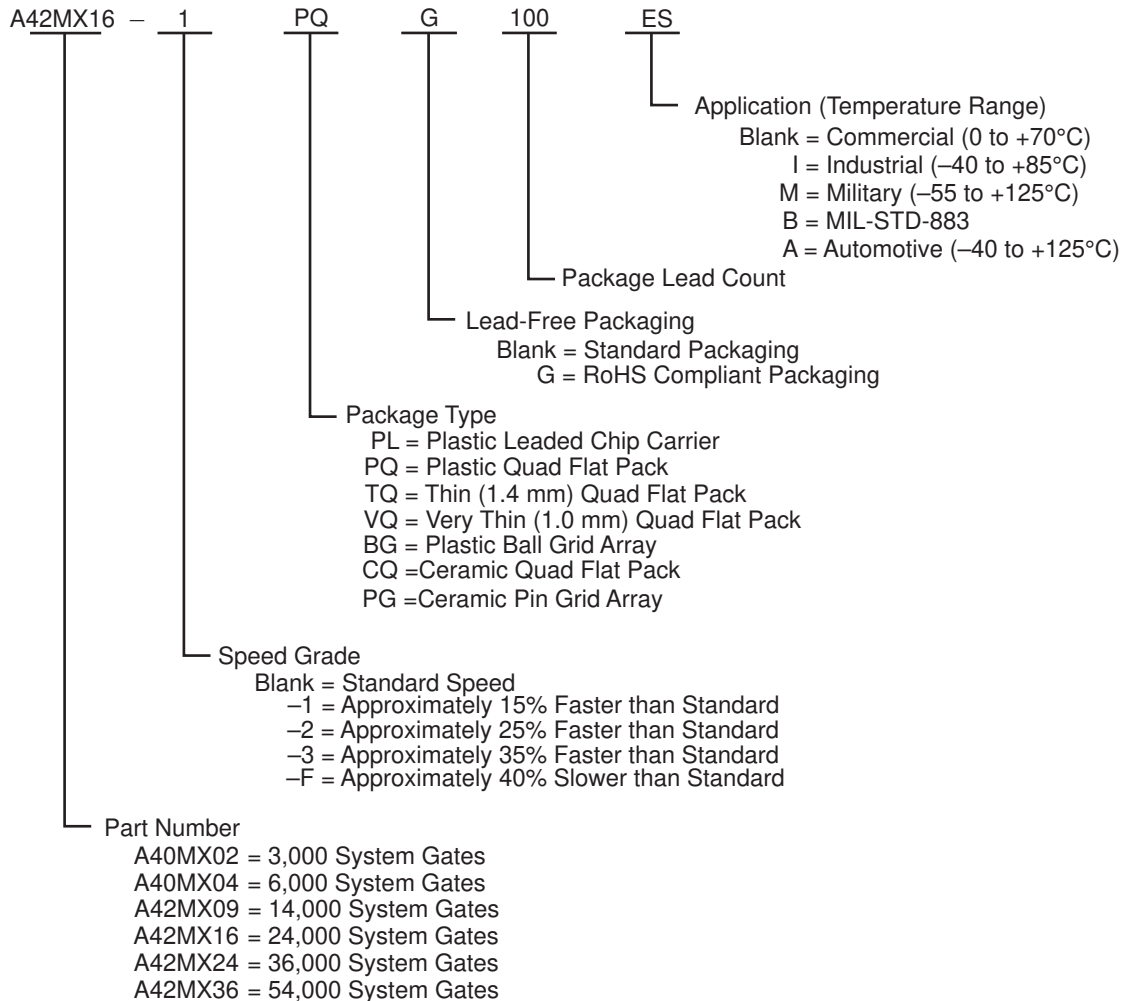
<b>Device</b>	<b>A40MX02</b>	<b>A40MX04</b>	<b>A42MX09</b>	<b>A42MX16</b>	<b>A42MX24</b>	<b>A42MX36</b>
<b>Maximum Flip-Flops</b>	147	273	516	928	1,410	1,822
<b>Clocks</b>	1	1	2	2	2	6
<b>User I/O (maximum)</b>	57	69	104	140	176	202
<b>PCI</b>	–	–	–	–	Yes	Yes
<b>Boundary Scan Test (BST)</b>	–	–	–	–	Yes	Yes
Packages (by pin count)						
PLCC	44, 68	44, 68, 84	84	84	84	–
PQFP	100	100	100, 144, 160	100, 160, 208	160, 208	208, 240
VQFP	80	80	100	100	–	–
TQFP	–	–	176	176	176	–
CQFP	–	–	–	172	–	208, 256
PBGA	–	–	–	–	–	272
CPGA	–	–	132	–	–	–



## 2.3 Ordering Information

The following figure shows ordering information. All the following tables show plastic and ceramic device resources, temperature and speed grade offerings.

**Figure 1 • Ordering Information**



## 2.4 Plastic Device Resources

**Table 2 • Plastic Device Resources**

Device	User I/Os											
	PLCC 44-Pin	PLCC 68-Pin	PLCC 84-Pin	PQFP 100-Pin	PQFP 144- Pin	PQFP 160-Pin	PQFP 208- Pin	PQFP 240-Pin	VQFP 80-Pin	VQFP 100- Pin	TQFP 176- Pin	PBGA 272- Pin
A40MX02	34	57	–	57	–	–	–	–	57	–	–	–
A40MX04	34	57	69	69	–	–	–	–	69	–	–	–
A42MX09	–	–	72	83	95	101	–	–	–	83	104	–
A42MX16	–	–	72	83	–	125	140	–	–	83	140	–
A42MX24	–	–	72	–	–	125	176	–	–	–	150	–
A42MX36	–	–	–	–	–	–	176	202	–	–	–	202

**Note: Package Definitions:** PLCC = Plastic Leaded Chip Carrier, PQFP = Plastic Quad Flat Pack, TQFP = Thin Quad Flat Pack, VQFP = Very Thin Quad Flat Pack, PBGA = Plastic Ball Grid Array

## 2.5 Ceramic Device Resources

**Table 3 • Ceramic Device Resources**

Device	User I/Os			
	CPGA 132-Pin	CQFP 172-Pin	CQFP 208-Pin	CQFP 256-Pin
A42MX09	95			
A42MX16		131		
A42MX36			176	202

**Note: Package Definitions:** CQFP = Ceramic Quad Flat Pack

## 2.6 Temperature Grade Offerings

**Table 4 • Temperature Grade Offerings**

Package	A40MX02	A40MX04	A42MX09	A42MX16	A42MX24	A42MX36
PLCC 44	C, I, M	C, I, M				
PLCC 68	C, I, A, M	C, I, M				
PLCC 84		C, I, A, M	C, I, A, M	C, I, M	C, I, M	
PQFP 100	C, I, A, M	C, I, A, M	C, I, A, M	C, I, M		
PQFP 144			C			
PQFP 160			C, I, A, M	C, I, M	C, I, A, M	
PQFP 208				C, I, A, M	C, I, A, M	C, I, A, M
PQFP 240						C, I, A, M
VQFP 80	C, I, A, M	C, I, A, M				
VQFP 100			C, I, A, M	C, I, A, M		
TQFP 176			C, I, A, M	C, I, A, M	C, I, A, M	
PBGA 272						C, I, M
CQFP 172				C, M, B		
CQFP 208						C, M, B
CQFP 256						C, M, B
CPGA 132			C, M, B			

**Note:** C = Commercial  
 I = Industrial  
 A = Automotive  
 M = Military  
 B = MIL-STD-883 Class B

## 2.7 Speed Grade Offerings

**Table 5 • Speed Grade Offerings**

	- F	Std	-1	-2	-3
C	P	P	P	P	P
I		P	P	P	P
A		P			
M		P	P		
B		P	P		

**Note:** See the [40MX and 42MX Automotive Family FPGAs](#) datasheet for details on automotive-grade MX offerings.

Contact your local [Microsemi Sales representative](#) for device availability.

## 3 40MX and 42MX FPGAs

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### 3.1 General Description

Microsemi's 40MX and 42MX families offer a cost-effective design solution at 5V. The MX devices are single-chip solutions and provide high performance while shortening the system design and development cycle. MX devices can integrate and consolidate logic implemented in multiple PALs, CPLDs, and FPGAs. Example applications include high-speed controllers and address decoding, peripheral bus interfaces, DSP, and co-processor functions.

The MX device architecture is based on Microsemi's patented antifuse technology implemented in a 0.45µm triple-metal CMOS process. With capacities ranging from 3,000 to 54,000 system gates, the MX devices provide performance up to 250 MHz, are live on power-up and have one-fifth the standby power consumption of comparable FPGAs. MX FPGAs provide up to 202 user I/Os and are available in a wide variety of packages and speed grades.

A42MX24 and A42MX36 devices also feature multiPlex I/Os, which support mixed-voltage systems, enable programmable PCI, deliver high-performance operation at both 5.0V and 3.3V, and provide a low-power mode. The devices are fully compliant with the PCI local bus specification (version 2.1). They deliver 200 MHz on-chip operation and 6.1 ns clock-to-output performance.

The 42MX24 and 42MX36 devices include system-level features such as IEEE Standard 1149.1 (JTAG) Boundary Scan Testing and fast wide-decode modules. In addition, the A42MX36 device offers dual-port SRAM for implementing fast FIFOs, LIFOs, and temporary data storage. The storage elements can efficiently address applications requiring wide data path manipulation and can perform transformation functions such as those required for telecommunications, networking, and DSP.

All MX devices are fully tested over automotive and military temperature ranges. In addition, the largest member of the family, the A42MX36, is available in both CQ208 and CQ256 ceramic packages screened to MIL-STD-883 levels. For easy prototyping and conversion from plastic to ceramic, the CQ208 and PQ208 devices are pin-compatible.

### 3.2 MX Architectural Overview

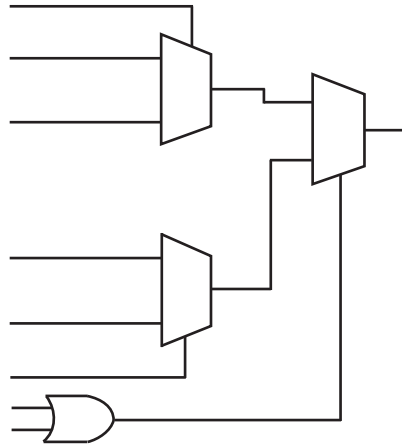
The MX devices are composed of fine-grained building blocks that enable fast, efficient logic designs. All devices within these families are composed of logic modules, I/O modules, routing resources and clock networks, which are the building blocks for fast logic designs. In addition, the A42MX36 device contains embedded dual-port SRAM modules, which are optimized for high-speed data path functions such as FIFOs, LIFOs and scratch pad memory. A42MX24 and A42MX36 also contain wide-decode modules.

#### 3.2.1 Logic Modules

The 40MX logic module is an eight-input, one-output logic circuit designed to implement a wide range of logic functions with efficient use of interconnect routing resources.(see the following figure).

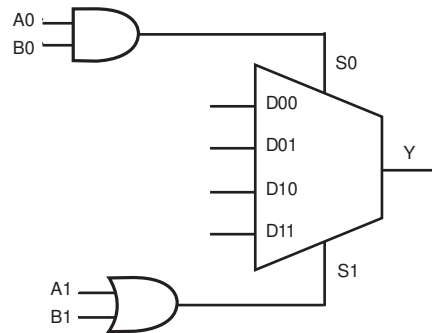
The logic module can implement the four basic logic functions (NAND, AND, OR and NOR) in gates of two, three, or four inputs. The logic module can also implement a variety of D-latches, exclusivity functions, AND-ORs and OR-ANDs. No dedicated hard-wired latches or flip-flops are required in the array; latches and flip-flops can be constructed from logic modules whenever required in the application.

**Figure 2 • 42MX C-Module Implementation**

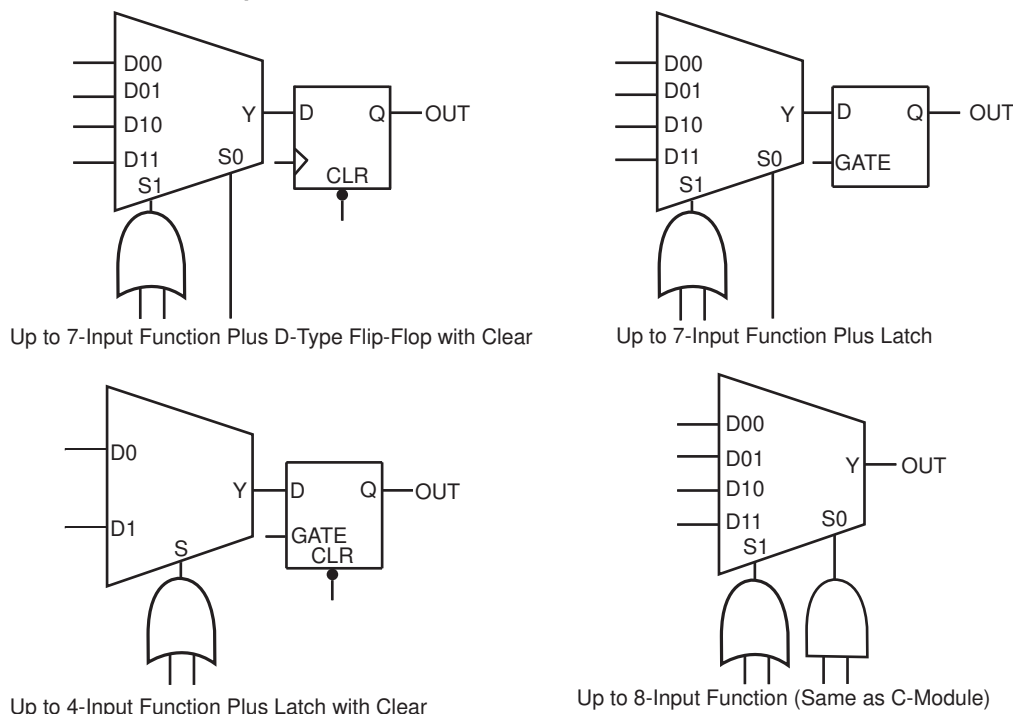


The 42MX devices contain three types of logic modules: combinatorial (C-modules), sequential (S-modules) and decode (D-modules). The following figure illustrates the combinatorial logic module. The S-module, shown in [Figure 4](#), page 8, implements the same combinatorial logic function as the C-module while adding a sequential element. The sequential element can be configured as either a D-flip-flop or a transparent latch. The S-module register can be bypassed so that it implements purely combinatorial logic.

**Figure 3 • 42MX C-Module Implementation**





**Figure 4 • 42MX S-Module Implementation**

A42MX24 and A42MX36 devices contain D-modules, which are arranged around the periphery of the device. D-modules contain wide-decode circuitry, providing a fast, wide-input AND function similar to that found in CPLD architectures (Figure 5, page 9). The D-module allows A42MX24 and A42MX36 devices to perform wide-decode functions at speeds comparable to CPLDs and PALs. The output of the D-module has a programmable inverter for active HIGH or LOW assertion. The D-module output is hardwired to an output pin, and can also be fed back into the array to be incorporated into other logic.

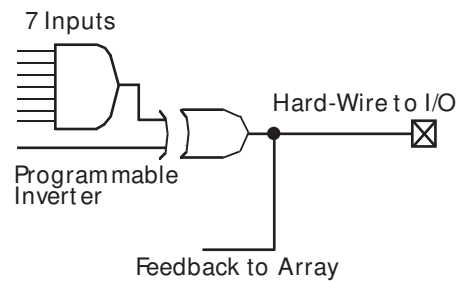
### 3.2.2 Dual-Port SRAM Modules

The A42MX36 device contains dual-port SRAM modules that have been optimized for synchronous or asynchronous applications. The SRAM modules are arranged in 256-bit blocks that can be configured as 32x8 or 64x4. SRAM modules can be cascaded together to form memory spaces of user-definable width and depth. A block diagram of the A42MX36 dual-port SRAM block is shown in Figure 6, page 9.

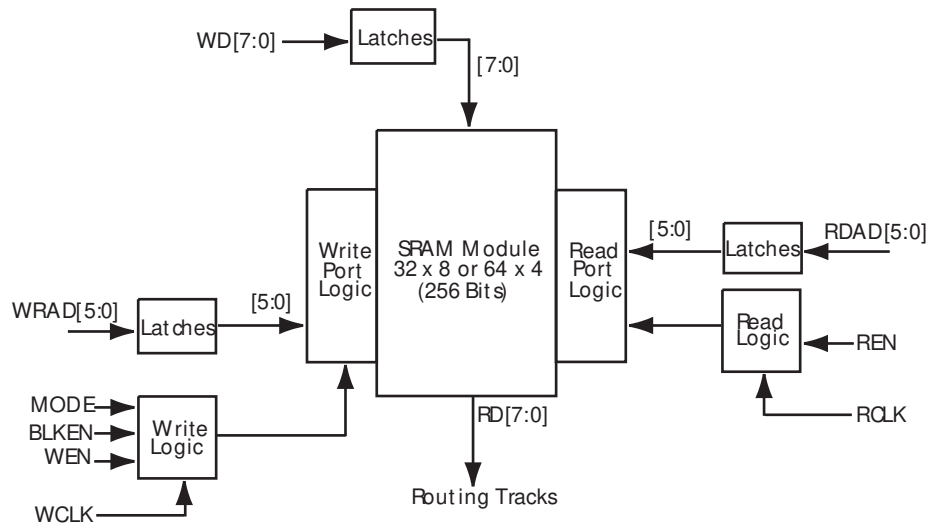
The A42MX36 SRAM modules are true dual-port structures containing independent read and write ports. Each SRAM module contains six bits of read and write addressing (RDAD[5:0] and WRAD[5:0], respectively) for 64x4-bit blocks. When configured in byte mode, the highest order address bits (RDAD5 and WRAD5) are not used. The read and write ports of the SRAM block contain independent clocks (RCLK and WCLK) with programmable polarities offering active HIGH or LOW implementation. The SRAM block contains eight data inputs (WD[7:0]), and eight outputs (RD[7:0]), which are connected to segmented vertical routing tracks.

The A42MX36 dual-port SRAM blocks provide an optimal solution for high-speed buffered applications requiring FIFO and LIFO queues. The ACTgen Macro Builder within Microsemi's designer software provides capability to quickly design memory functions with the SRAM blocks. Unused SRAM blocks can be used to implement registers for other user logic within the design.

**Figure 5 • A42MX24 and A42MX36 D-Module Implementation**



**Figure 6 • A42MX36 Dual-Port SRAM Block**



## 3.2.3 Routing Structure

The MX architecture uses vertical and horizontal routing tracks to interconnect the various logic and I/O modules. These routing tracks are metal interconnects that may be continuous or split into segments. Varying segment lengths allow the interconnect of over 90% of design tracks to occur with only two antifuse connections. Segments can be joined together at the ends using antifuses to increase their lengths up to the full length of the track. All interconnects can be accomplished with a maximum of four antifuses.

### 3.2.3.1 Horizontal Routing

Horizontal routing tracks span the whole row length or are divided into multiple segments and are located in between the rows of modules. Any segment that spans more than one-third of the row length is considered a long horizontal segment. A typical channel is shown in [Figure 7](#), page 10. Within horizontal routing, dedicated routing tracks are used for global clock networks and for power and ground tie-off tracks. Non-dedicated tracks are used for signal nets.

### 3.2.3.2 Vertical Routing

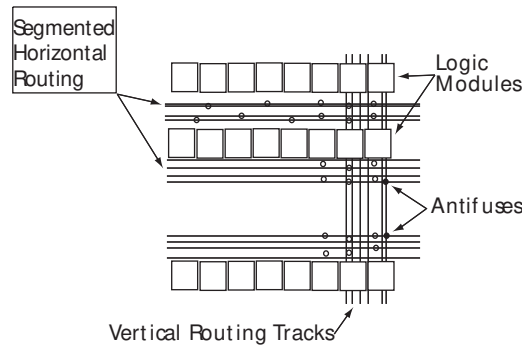
Another set of routing tracks run vertically through the module. There are three types of vertical tracks: input, output, and long. Long tracks span the column length of the module, and can be divided into multiple segments. Each segment in an input track is dedicated to the input of a particular module; each segment in an output track is dedicated to the output of a particular module. Long segments are uncommitted and can be assigned during routing.

Each output segment spans four channels (two above and two below), except near the top and bottom of the array, where edge effects occur. Long vertical tracks contain either one or two segments. An example of vertical routing tracks and segments is shown in [Figure 7](#), page 10.

### 3.2.3.3 Antifuse Structures

An antifuse is a “normally open” structure. The use of antifuses to implement a programmable logic device results in highly testable structures as well as efficient programming algorithms. There are no pre-existing connections; temporary connections can be made using pass transistors. These temporary connections can isolate individual antifuses to be programmed and individual circuit structures to be tested, which can be done before and after programming. For instance, all metal tracks can be tested for continuity and shorts between adjacent tracks, and the functionality of all logic modules can be verified.

**Figure 7 • MX Routing Structure**



### 3.2.4 Clock Networks

The 40MX devices have one global clock distribution network (CLK). A signal can be put on the CLK network by being routed through the CLKBUF buffer.

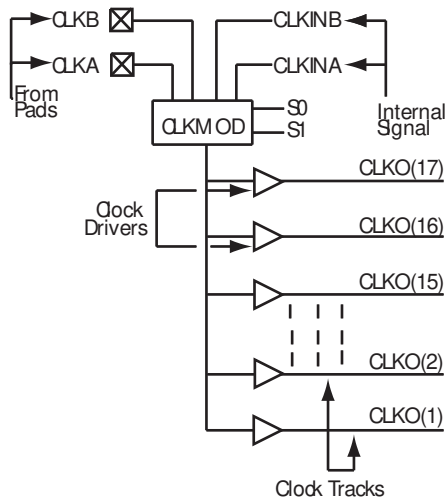
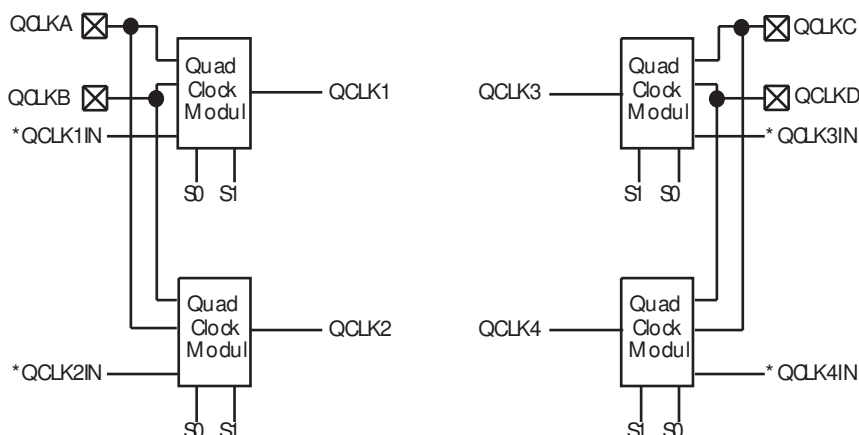
In 42MX devices, there are two low-skew, high-fanout clock distribution networks, referred to as CLKA and CLKB. Each network has a clock module (CLKMOD) that can select the source of the clock signal from any of the following (Figure 8, page 11):

- Externally from the CLKA pad, using CLKBUF buffer
- Externally from the CLKB pad, using CLKBUF buffer
- Internally from the CLKINTA input, using CLKINT buffer
- Internally from the CLKINTB input, using CLKINT buffer

The clock modules are located in the top row of I/O modules. Clock drivers and a dedicated horizontal clock track are located in each horizontal routing channel.

Clock input pads in both 40MX and 42MX devices can also be used as normal I/Os, bypassing the clock networks.

The A42MX36 device has four additional register control resources, called quadrant clock networks (Figure 9, page 11). Each quadrant clock provides a local, high-fanout resource to the contiguous logic modules within its quadrant of the device. Quadrant clock signals can originate from specific I/O pins or from the internal array and can be used as a secondary register clock, register clear, or output enable.

**Figure 8 • Clock Networks of 42MX Devices****Figure 9 • Quadrant Clock Network of A42MX36 Devices**

**Note:** \*QCLK1IN, QCLK2IN, QCLK3IN, and QCLK4IN are internally-generated signals.

### 3.2.5 MultiPlex I/O Modules

42MX devices feature MultiPlex I/Os and support 5.0 V, 3.3 V, and mixed 3.3 V/5.0 V operations.

The MultiPlex I/O modules provide the interface between the device pins and the logic array. Figure 10, page 12 is a block diagram of the 42MX I/O module. A variety of user functions, determined by a library macro selection, can be implemented in the module. (See the *Antifuse Macro Library Guide* for more information.) All 42MX I/O modules contain tristate buffers, with input and output latches that can be configured for input, output, or bidirectional operation.

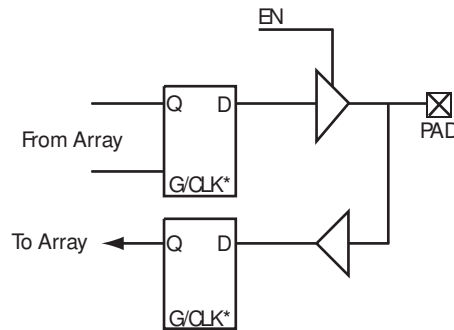
All 42MX devices contain flexible I/O structures, where each output pin has a dedicated output-enable control (Figure 10, page 12). The I/O module can be used to latch input or output data, or both, providing fast set-up time. In addition, the Designer software tools can build a D-type flip-flop using a C-module combined with an I/O module to register input and output signals. See the *Antifuse Macro Library Guide* for more details.

A42MX24 and A42MX36 devices also offer selectable PCI output drives, enabling 100% compliance with version 2.1 of the PCI specification. For low-power systems, all inputs and outputs are turned off to reduce current consumption to below 500  $\mu$ A.

To achieve 5.0 V or 3.3 V PCI-compliant output drives on A42MX24 and A42MX36 devices, a chip-wide PCI fuse is programmed via the Device Selection Wizard in the Designer software (Figure 11, page 12). When the PCI fuse is not programmed, the output drive is standard.

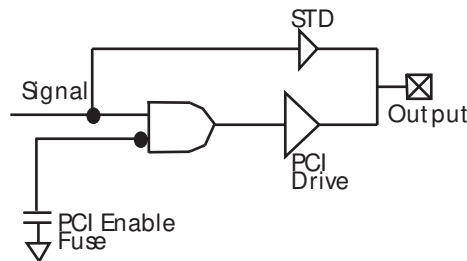
Designer software development tools provide a design library of I/O macro functions that can implement all I/O configurations supported by the MX FPGAs.

**Figure 10 • 42MX I/O Module**



**Note:** \*Can be configured as a Latch or D Flip-Flop (Using C-Module)

**Figure 11 • PCI Output Structure of A42MX24 and A42MX36 Devices**



## 3.3 Other Architectural Features

The following sections cover other architectural features of 40MX and 42MX FPGAs.

### 3.3.1 Performance

MX devices can operate with internal clock frequencies of 250 MHz, enabling fast execution of complex logic functions. MX devices are live on power-up and do not require auxiliary configuration devices and thus are an optimal platform to integrate the functionality contained in multiple programmable logic devices. In addition, designs that previously would have required a gate array to meet performance can be integrated into an MX device with improvements in cost and time-to-market. Using timing-driven place-and-route (TDPR) tools, designers can achieve highly deterministic device performance.

### 3.3.2 User Security

Microsemi FuseLock provides robust security against design theft. Special security fuses are hidden in the fabric of the device and protect against unauthorized users attempting to access the programming and/or probe interfaces. It is virtually impossible to identify or bypass these fuses without damaging the device, making Microsemi antifuse FPGAs protected with the highest level of security available from both invasive and noninvasive attacks.

Special security fuses in 40MX devices include the Probe Fuse and Program Fuse. The former disables the probing circuitry while the latter prohibits further programming of all fuses, including the Probe Fuse. In 42MX devices, there is the Security Fuse which, when programmed, both disables the probing circuitry and prohibits further programming of the device.

### 3.3.3 Programming

Device programming is supported through the Silicon Sculptor series of programmers. Silicon Sculptor is a compact, robust, single-site and multi-site device programmer for the PC. With standalone software, Silicon Sculptor is designed to allow concurrent programming of multiple units from the same PC.



Silicon Sculptor programs devices independently to achieve the fastest programming times possible. After being programmed, each fuse is verified to insure that it has been programmed correctly. Furthermore, at the end of programming, there are integrity tests that are run to ensure no extra fuses have been programmed. Not only does it test fuses (both programmed and non-programmed), Silicon Sculptor also allows self-test to verify its own hardware extensively.

The procedure for programming an MX device using Silicon Sculptor is as follows:

1. Load the \*.AFM file
2. Select the device to be programmed
3. Begin programming

When the design is ready to go to production, Microsemi offers device volume-programming services either through distribution partners or via In-House Programming from the factory.

For more details on programming MX devices, see the [AC225: Programming Antifuse Devices](#) application note and the [Silicon Sculptor 3 Programmers User Guide](#).

### 3.3.4 Power Supply

MX devices are designed to operate in both 5.0V and 3.3V environments. In particular, 42MX devices can operate in mixed 5.0 V/3.3 V systems. The following table describes the voltage support of MX devices.

**Table 6 • Voltage Support of MX Devices**

Device	VCC	VCCA	VCCI	Maximum Input Tolerance	Nominal Output Voltage
40MX	5.0 V	–	–	5.5 V	5.0 V
	3.3 V	–	–	3.6 V	3.3 V
42MX	–	5.0 V	5.0 V	5.5 V	5.0 V
	–	3.3 V	3.3 V	3.6 V	3.3 V
	–	5.0 V	3.3 V	5.5 V	3.3 V

For A42MX24 and A42MX36 devices the VCCA supply has to be monotonic during power up in order for the POR to issue reset to the JTAG state machine correctly. For more information, see the [AC291: 42MX Family Devices Power-Up Behavior](#).

### 3.3.5 Power-Up/Down in Mixed-Voltage Mode

When powering up 42MX in mixed voltage mode (VCCA = 5.0 V and VCCI = 3.3 V), VCCA must be greater than or equal to VCCI throughout the power-up sequence. If VCCI exceeds VCCA during power-up, one of two things will happen:

- The input protection diode on the I/Os will be forward biased
- The I/Os will be at logical High

In either case, ICC rises to high levels. For power-down, any sequence with VCCA and VCCI can be implemented.

### 3.3.6 Transient Current

Due to the simultaneous random logic switching activity during power-up, a transient current may appear on the core supply (VCC). Customers must use a regulator for the VCC supply that can source a minimum of 100 mA for transient current during power-up. Failure to provide enough power can prevent the system from powering up properly and result in functional failure. However, there are no reliability concerns, since transient current is distributed across the die instead of confined to a localized spot.

Since the transient current is not due to I/O switching, its value and duration are independent of the VCCI.

### 3.3.7 Low Power Mode

42MX devices have been designed with a Low Power Mode. This feature, activated with setting the special LP pin to HIGH for a period longer than 800 ns, is particularly useful for battery-operated systems where battery life is a primary concern. In this mode, the core of the device is turned off and the device consumes minimal power with low standby current. In addition, all input buffers are turned off, and all outputs and bidirectional buffers are tristated. Since the core of the device is turned off, the states of the registers are lost. The device must be re-initialized when exiting Low Power Mode. I/Os can be driven during LP mode, and clock pins should be driven HIGH or LOW and should not float to avoid drawing current. To exit LP mode, the LP pin must be pulled LOW for over 200  $\mu$ s to allow for charge pumps to power up, and device initialization will begin.

## 3.4 Power Dissipation

The general power consumption of MX devices is made up of static and dynamic power and can be expressed with the following equation.

### 3.4.1 General Power Equation

$$P = [ICC_{standby} + ICC_{active}] * V_{CCI} + IOL * VOL * N + IOH * (V_{CCI} - VOH) * M$$

EQ 1

where:

- $ICC_{standby}$  is the current flowing when no inputs or outputs are changing.
- $ICC_{active}$  is the current flowing due to CMOS switching.
- $IOL$ ,  $IOH$  are TTL sink/source currents.
- $VOL$ ,  $VOH$  are TTL level output voltages.
- $N$  equals the number of outputs driving TTL loads to  $VOL$ .
- $M$  equals the number of outputs driving TTL loads to  $VOH$ .

Accurate values for  $N$  and  $M$  are difficult to determine because they depend on the family type, on design details, and on the system I/O. The power can be divided into two components: static and active.

### 3.4.2 Static Power Component

The static power due to standby current is typically a small component of the overall power consumption. Standby power is calculated for commercial, worst-case conditions. The static power dissipation by TTL loads depends on the number of outputs driving, and on the DC load current. For instance, a 32-bit bus sinking 4mA at 0.33V will generate 42mW with all outputs driving LOW, and 140mW with all outputs driving HIGH. The actual dissipation will average somewhere in between, as I/Os switch states with time.

### 3.4.3 Active Power Component

Power dissipation in CMOS devices is usually dominated by the dynamic power dissipation. Dynamic power consumption is frequency-dependent and is a function of the logic and the external I/O. Active power dissipation results from charging internal chip capacitances of the interconnect, unprogrammed antifuses, module inputs, and module outputs, plus external capacitances due to PC board traces and load device inputs. An additional component of the active power dissipation is the totem pole current in the CMOS transistor pairs. The net effect can be associated with an equivalent capacitance that can be combined with frequency and voltage to represent active power dissipation.

The power dissipated by a CMOS circuit can be expressed by the equation:

$$\text{Power}(\mu\text{W}) = C_{EQ} * V_{CCA}^2 * F(1)$$

EQ 2

where:

- $C_{EQ}$  = Equivalent capacitance expressed in picofarads (pF)

- $V_{CCA}$  = Power supply in volts (V)
- $F$  = Switching frequency in megahertz (MHz)

### 3.4.4 Equivalent Capacitance

Equivalent capacitance is calculated by measuring  $I_{CCActive}$  at a specified frequency and voltage for each circuit component of interest. Measurements have been made over a range of frequencies at a fixed value of VCC. Equivalent capacitance is frequency-independent, so the results can be used over a wide range of operating conditions. Equivalent capacitance values are shown below.

### 3.4.5 $C_{EQ}$ Values for Microsemi MX FPGAs

Modules ( $C_{EQM}$ ) 3.5

Input Buffers ( $C_{EQI}$ ) 6.9

Output Buffers ( $C_{EQO}$ ) 18.2

Routed Array Clock Buffer Loads ( $C_{EQCR}$ ) 1.4

To calculate the active power dissipated from the complete design, the switching frequency of each part of the logic must be known. The equation below shows a piece-wise linear summation over all components.

$$\text{Power} = V_{CCA}^2 * [(m * C_{EQM} * f_m)_{\text{modules}} + (n * C_{EQI} * f_n)_{\text{inputs}} + (p * (C_{EQO} + C_L) * f_p)_{\text{outputs}} + 0.5 * (q_1 * C_{EQCR} * f_{q1})_{\text{routed\_clk1}} + (r_1 * f_{q1})_{\text{routed\_clk1}} + 0.5 * (q_2 * C_{EQCR} * f_{q2})_{\text{routed\_clk2}} + (r_2 * f_{q2})_{\text{routed\_clk2}}] \quad (2)$$

**EQ 3**

where:

$m$  = Number of logic modules switching at frequency  $f_m$

$n$  = Number of input buffers switching at frequency  $f_n$

$p$  = Number of output buffers switching at frequency  $f_p$

$q_1$  = Number of clock loads on the first routed array clock

$q_2$  = Number of clock loads on the second routed array clock

$r_1$  = Fixed capacitance due to first routed array clock

$r_2$  = Fixed capacitance due to second routed array clock

$C_{EQM}$  = Equivalent capacitance of logic modules in pF

$C_{EQI}$  = Equivalent capacitance of input buffers in pF

$C_{EQO}$  = Equivalent capacitance of output buffers in pF

$C_{EQCR}$  = Equivalent capacitance of routed array clock in pF

$C_L$  = Output load capacitance in pF

$f_m$  = Average logic module switching rate in MHz

$f_n$  = Average input buffer switching rate in MHz

$f_p$  = Average output buffer switching rate in MHz

$f_{q1}$  = Average first routed array clock rate in MHz